

학술행사  
(Conference)

학술대회 안내 (Overview)

전체 일정 (Program at a Glance)

기조강연 (Plenary Lecturers)

반도체 국제 심포지엄  
(International Symposium  
on Semiconductor  
Technology and  
Characterization)

특별 심포지엄 (Symposia)

논문발표 안내 (Author  
introductions)

등록안내 (Registration)

초록제출 (Abstracts)

숙박 안내 (Accommodation)

지난 학술대회 (Past  
Conferences)

회원 정보

이은지님 반갑습니다.

인증    정회원

회원정보 확인 및 수정

사용종료 (로그아웃)

특별 심포지엄 (Symposia)

IP1    Advanced functional  
microscopy and  
spectroscopy

IP2    Advances in SEM/FIB and  
EBSD for High-Resolution  
Imaging and Structural  
AnalysisIP

IP3    Advanced scanning probe  
microscopy studies in  
functional materials

IP4    Big data- and AI agent-  
driven research

IP5    3d imaging

IP6    Volume Microscopy

IP7    X-ray microscopy

LMP1    Advanced Energy  
Materials

LMP2    Semiconductor Materials  
and Characterization

LMP3    Cryo-EM Research on  
Challenging Protein  
Complexes

LMP4    Nano-Optical Imaging

SP1    Analysis methods for  
secondary battery and  
battery materials and  
technology exchange  
related to the  
preprocessing process of  
materials

SP2    International Symposium  
on Semiconductor  
Technology and  
Characterization

SP3    Satellite Symposium

Advanced functional microscopy and spectroscopy

Introduction

This session will include TEM studies of the structure, phases, nucleation, growth, defects, interfaces, and surfaces in nano-materials, such as 2D crystals, nanorod, nanodot, thin films, and nanocrystals, as well as direct imaging and 3D imaging of soft materials (organic or bio-materials) using the application of aberration-corrected scanning/transmission electron microscope (S/TEM), electron diffraction, energy-dispersive X-ray spectroscopy (EDS), and electron energy loss spectroscopy (EELS), 4D-STEM

Topics

aberration-corrected scanning/transmission electron microscope (S/TEM), electron diffraction, energy-dispersive X-ray spectroscopy (EDS), and electron energy loss spectroscopy (EELS) 4D-STEM, Ptychography, in-situ TEM, battery, semiconductor, metal, catalyst, instrumentation, cryo TEM, 3D analysis, protein

Invited Speakers

Speaker

박정재

<b>Affiliation</b>	RIST
<b>Presentation title</b>	Corrosion behaviors of Zn-Al-Mg Alloys revealed by liquid-phase TEM
<b>Speaker</b>	구건모
<b>Affiliation</b>	부산대학교
<b>Presentation title</b>	Thermomechanical Disproportionation of Silicon Oxynitride at Closed-Cell Environmental Transmission Electron Microscopy
<b>Speaker</b>	박재열
<b>Affiliation</b>	KIER
<b>Presentation title</b>	Transmission Electron Microscopy of Layered Cathodes for Rechargeable Batteries
<b>Speaker</b>	장준하
<b>Affiliation</b>	RIST
<b>Presentation title</b>	Analysis of degradation mechanism of layered oxide cathodes for lithium-ion battery using transmission electron microscopy
<b>Speaker</b>	김나연
<b>Affiliation</b>	KIMS
<b>Presentation title</b>	Transforming Electron Microscopy: Ptychography as a Bridge to Multimodal Atomic Imaging
<b>Speaker</b>	한상섭
<b>Affiliation</b>	KBSI
<b>Presentation title</b>	Heterogeneous 2D TMDs Integration: From Growth to Future Electronics
<b>Speaker</b>	이은지
<b>Affiliation</b>	GIST
<b>Presentation title</b>	Decoding the cellular self-assembled nanoparticles by cryo-TEM
<b>Speaker</b>	정민교
<b>Affiliation</b>	한국뇌연구원
<b>Presentation title</b>	Spatiotemporal tracking of intracellular nanoparticles using complementary imaging techniques

TOP

Korean Society of Microscopy

개인정보취급방침

첫페이지



(사)한국현미경학회 (고유번호 : 209-82-06363, 대표자 : 여중석)

주소 : 02794, 서울특별시 성북구 월곡로 14길 24 월곡래미안 루나밸리 상가 303호 대표전화 : 02-919-8775

전자우편 : office@microscopy.or.kr

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